



INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet	1	of	2
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Complete if Known

Application Number	10/689,241
Filing Date	10/20/2003
First Named Inventor	Zaidi
Art Unit	2877
Examiner Name	TBD
Attorney Docket Number	02 P 50491 US/INTECH 3.0-087

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

**Examiner
Signature**

Michael Statina

Date
Considered

10-21-05

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Substitute for form 1449B/PTO		Complete If Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Application Number	10/689,241
		Filing Date	10/20/2003
		First Named Inventor	Zaidi
		Art Unit	2877
		Examiner Name	TBD
(Use as many sheets as necessary)		Attorney Docket Number	02 P 50491 US/INTECH 3.0-087
Sheet	2	of	2

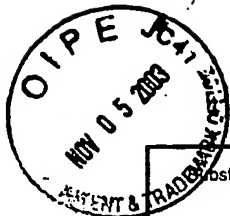
NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
MS	11	BOGDANOV, V., et al., "Parallel, confocal, and complete spectrum imager for fluorescent detection of high-density microarray," Part of the SPIE Conference on Multidimensional Spectroscopy: Acquisition, Interpretation, and Automation, January 1999, pp. 298-307, Vol. 3605.	

Examiner Signature	M. Michael Stahl	Date Considered	10-21-05
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Institute for form 1449A/B/PTO			Complete If Known		
			Application Number	10/689,241	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)			Filing Date	October 20, 2003	
			First Named Inventor	Syed Shoaib Hasan Zaidi	
			Art Unit	N/A	
			Examiner Name	Not Yet Assigned	
			Attorney Docket Number	INTECH 3.0-087	
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U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
JS	AA	US-2003/0063278-A1	04-03-2003	Zaidi	
JS	AB	US-2003/0133127-A1	07-17-2003	Zaidi, et al.	
JS	AC	US-6,548,314-B1	04-15-2003	Zaidi	
JS	AD	US-6,596,377-B1	07-22-2003	Hersee et al.	
JS	AE	US-6,320,648-B1	11-20-2001	Brueck et al.	
JS	AF	US-6,233,044-B1	05-15-2001	Brueck et al.	
JS	AG	US-6,042,998-B1	03-28-2000	Brueck et al.	
JS	AH	US-Re. 36,113-E	02-23-1999	Brueck et al.	
JS	AI	US-5,759,744-B1	06-02-1998	Brueck et al.	
JS	AJ	US-5,705,321-B1	01-06-1998	Brueck et al.	
JS	AK	US-5,415,835-B1	05-16-1995	Brueck, et al.	

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

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NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			
JS	CA	Sui, et al., "Integrated Process Control Using an In Situ Sensor for Etch," Solid State Technology, April, 2002			
JS	CB	Herrick, et al., "Using Broadband Reflectometry for Fast Trench-Depth Measurement," Solid State Technology, February, 2003			
JS	CC	Logofatu, "Tools for Testing - A Non-Contact, Nondestructive Option for Characterizing Lithography Test Samples, Scatterometry Performance Improves," Spie's OE Magazine, August, 2003, pp. 40-42			
	CD	Seller, et al., "Challenges of Metrology and Characterization Measurements for ULSI Technology," National Institute of Standards and Technology, pp. 150-166			
	CE	McNeill, "Scatterometry Applied to Microelectronics Processing," www.ieee.org/organizations/pubs/newletters/leost/oct00/scatter.html			
	CF	"The Shack-Hartmann Sensor," www.polytec-pt.fr/wavefrontsciences/ophthalmic/hartmannsensor.html			
	CG	"The Shack-Hartmann Sensor," www.wavefrontsciences.com/ophthalmic/hartmannsensor.html			

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* Line through citations not considered because they fail to provide a date of publication.